

<b>Notic of R ferenc s Cited</b>	Application/Control No. 10/724,164		Applicant(s)/Patent Under Reexamination HIROSE, YUKITOSHI	
	Examiner Arpan P. Savla		Art Unit 2185	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0069317	06-2002	Chow et al.	711/104
*	B	US-5,586,291	12-1996	Lasker et al.	711/113
*	C	US-6,411,539	06-2002	Funaba et al.	365/63
*	D	US-6,487,623	11-2002	Emerson et al.	710/302
*	E	US-2002/0083255	06-2002	Greeff et al.	710/305
*	F	US-6,263,452	07-2001	Jewett et al.	714/9
*	G	US-6,571,324	05-2003	Elkington et al.	711/162
*	H	US-6,766,469	07-2004	Larson et al.	714/7
*	I	US-6,871,253	03-2005	Greeff et al.	710/316
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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